

EE412

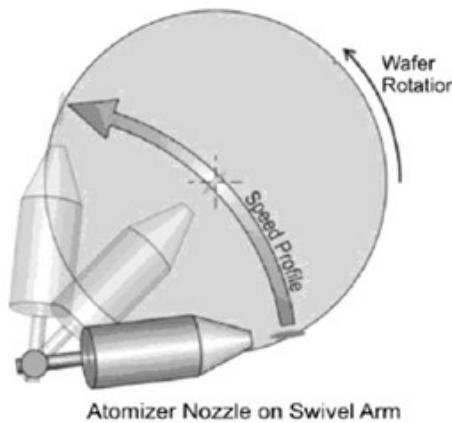
Deep Trench Spray Coating

Final Presentation

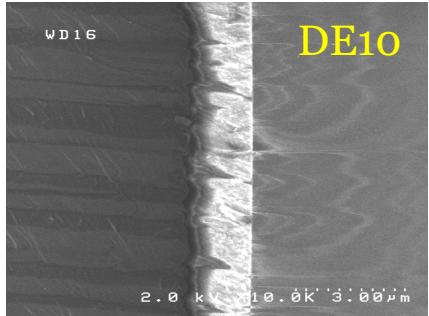
Karthik Vijayraghavan
Mentor : Jason Parker

12/08/2010

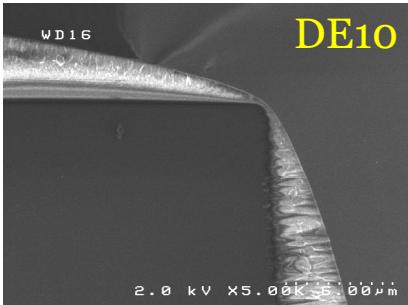
Introduction - EV101 Spraycoater



Sidewall
(250um deep)

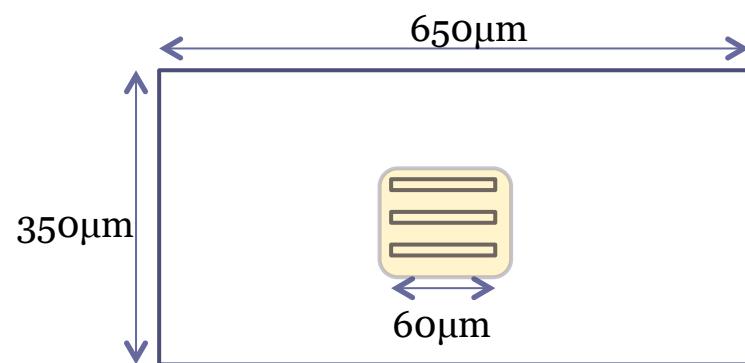


Corner

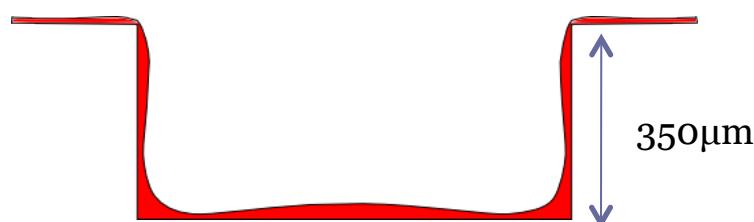


- Sprays a resist mixture using an ultrasonic nozzle. Typical droplet diameter $\sim 20\text{um}$
- Low spin speeds (30rpm – 60rpm)
- Resist thickness is typically 10um+. Lower thickness possible if
 - Shallow features, or
 - Deep features but large areas to fill resist
- Can be used to protect sidewalls and corners with resist
- Uses relatively little resist material
- Both, planar and conformal coatings possible using different nozzles ('vortex' and 'accumist')

Objectives



Top View



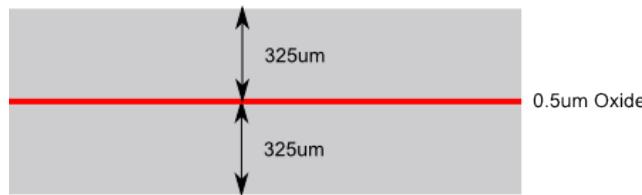
X-Section View

- Obtain a uniform coat of photoresist with thickness $< 3\mu\text{m}$ in the region of interest at the bottom of a 350μm deep 350μm x 650μm DRIE trench coated with silicon nitride
- Thickness variation $< 0.5\mu\text{m}$
- Expose test pattern in ASML using the MSI patch to test resolution limits
- Starting recipe was Pierres Ponce's P44

12/08/2010

Wafer Preparation

1



Fusion bond two R-prime wafers using the teflon jig with 0.5um oxide on handle. Exact procedure in wiki

2



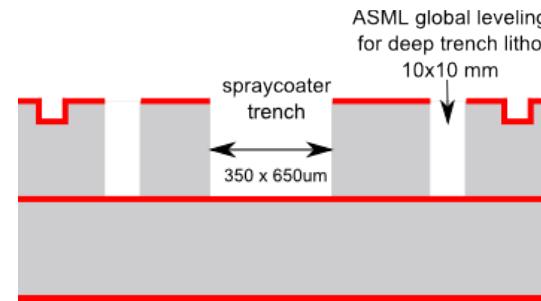
ASML alignment marks

3



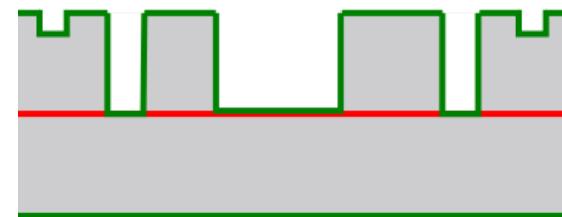
Deposit 3um LTO and pattern trenches

4



Sts2 DRIE etch through top wafer

5



Strip masking oxide and BOX in 6:1 BOE. Deposit nitride

6

Before coating 20min in 9:1 piranha
Followed by HMDS prime in YES oven

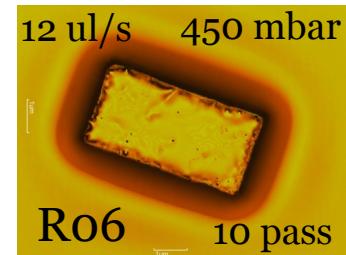
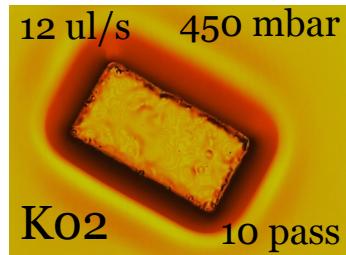
Parameters Explored

- Resist mixture consists of:
 - Photoresist SPR 220-7 (4.8% - 11.4%)
 - Low vapor pressure solvent Ethyl Lactate (25% - 45%)
 - High vapor pressure solvent MEK (remaining)
- Resist mixture dispense rate (3ul/s – 15ul/s)
- Nozzle pressure (300mbar – 900mbar)
- Number of passes (5 – 15)
- Velocity profile
- Heated chuck was used and set at 75C
- Total of 91 experiments exploring different combination of parameters. All results available on wiki

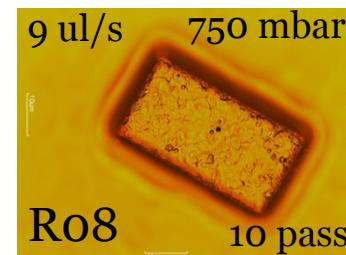
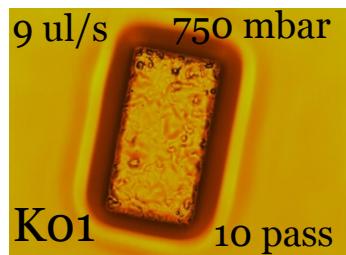
Repeatability

- Experimental results are repeatable

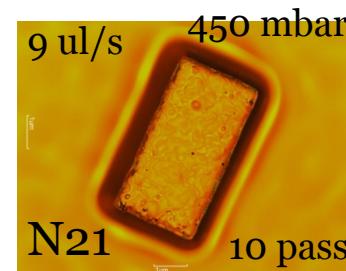
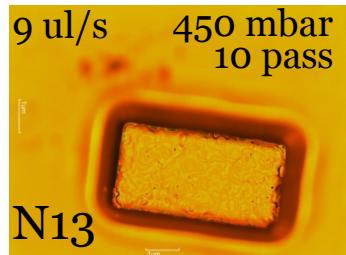
7.7% Resist
25% LVP



7.7% Resist
25% LVP



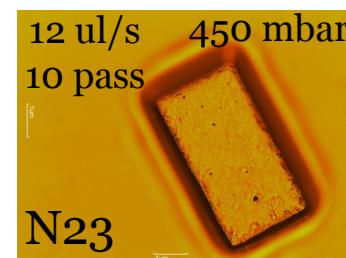
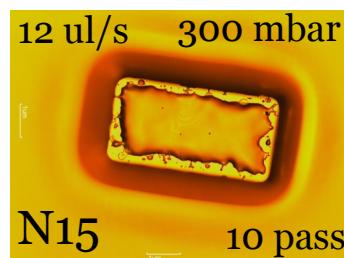
5% Resist
45% LVP



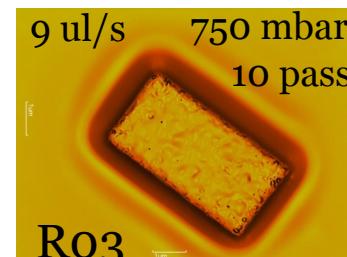
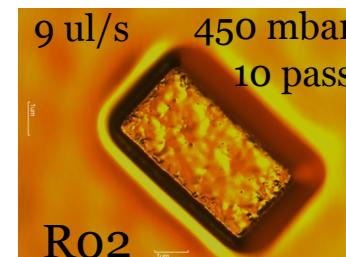
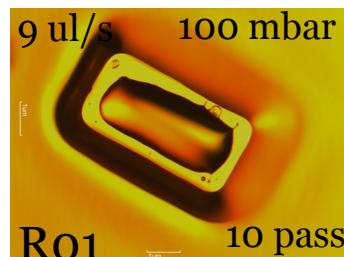
Effect of Pressure

- Higher pressure improves uniformity and causes less pooling of resist at the bottom of trench

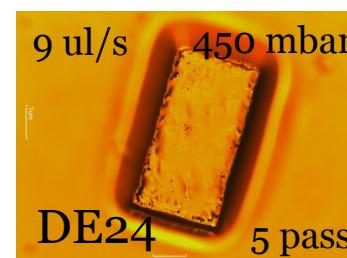
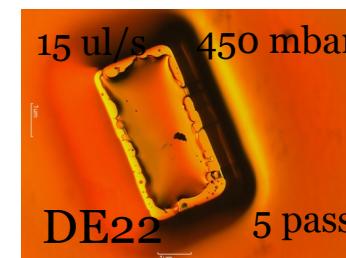
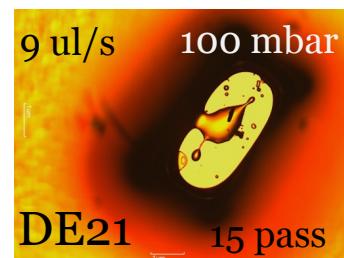
5% Resist
45% LVP



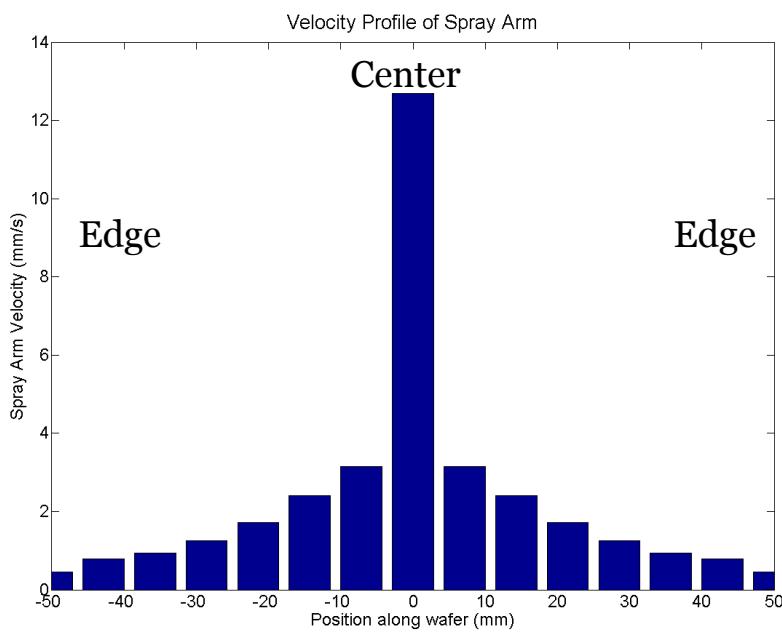
5% Resist
25% LVP



11.5% Resist
44.6% LVP

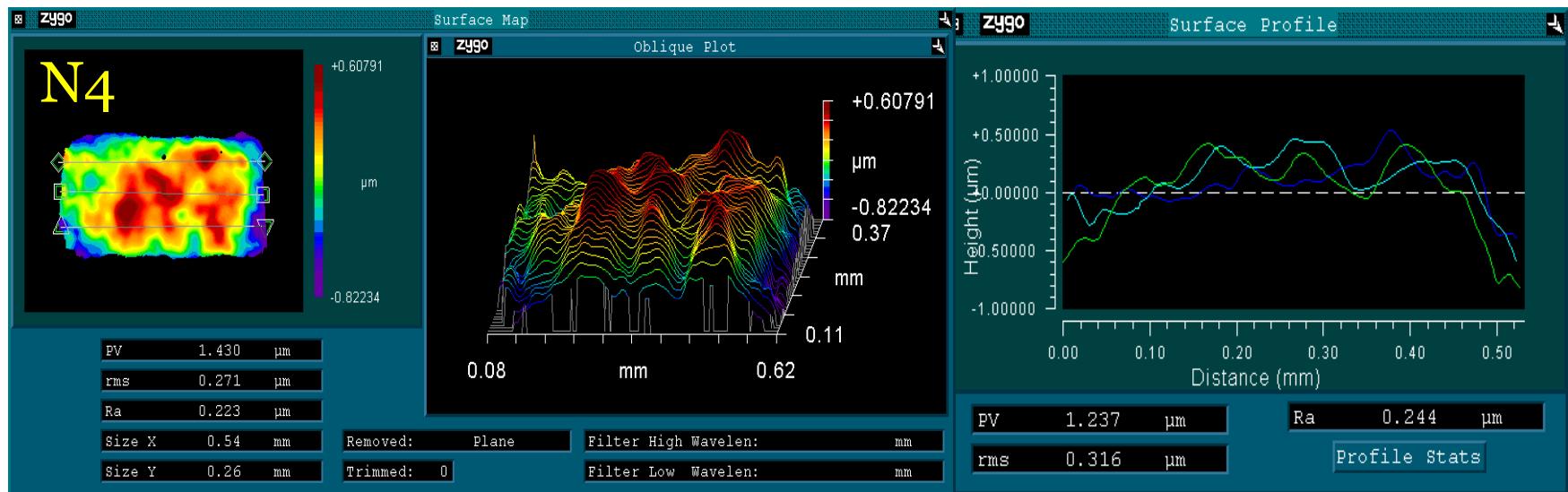


Velocity Profile



- Area to be coated is higher at edge as compared to center. Hence, velocity needs to be adjusted to obtain uniform coating thickness
- Velocity profile can be scaled to increase or decrease overall time per pass
- Scaling also changes dispense rate if thickness is to be kept constant
- Slow passes lead to less rough films. But can cause resist pooling due to large quantity of resist being dispensed

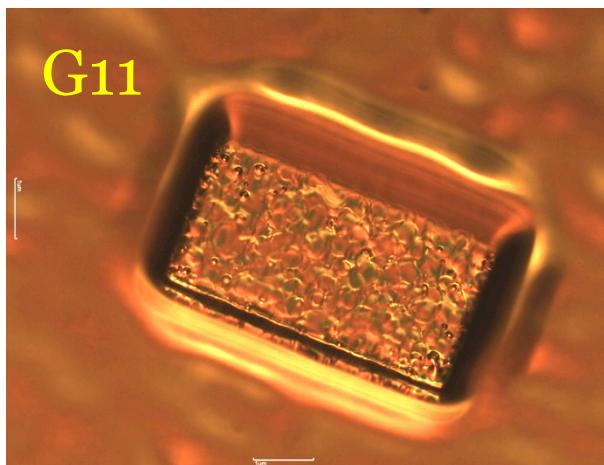
Zygo Results (Jason)



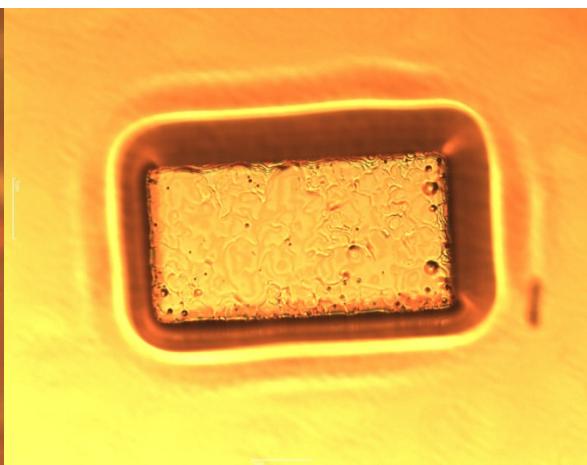
- Zygo measurements on select samples. Full results on wiki
- Samples coated with 300A of Aluminum
- Surface roughness for above sample:
 - Ra = 0.223μm
 - RMS = 0.271μm

Recipe Used For ASML Exposure Testing

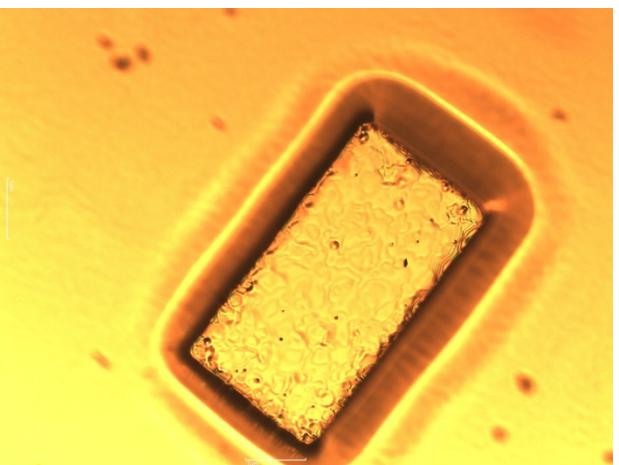
Center



Mid



Edge

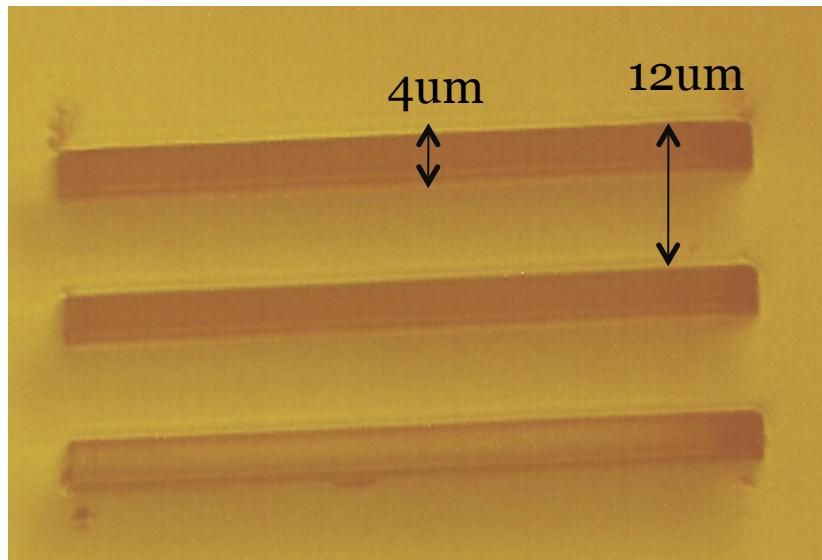


- Resist Mix : 5% SPR 220-7, 35% Ethyl Lactate, 60% MEK
- Dispense rate: 9ul/s, Pressure: 600mbar, Passes: 12

Deep Trench Lithography With ASML

- ASML in ‘normal’ mode
 - Cannot apply focus offsets of more than 30um
 - Global leveling is done at three points which are not user controllable. If deep features are present the wafer can get rejected
- ASML in special ‘MSI’ patch mode
 - Gives user control of level sensor locations. However need large area (10 x 10mm)
- Deep trench lithography possible if 3 large 10 x 10mm squares (GL openings) are etched to the same level as features to be exposed
- GL openings need to have low roughness

Exposure Testing with ASML



- 4um features could be resolved in the large 10mm x 10mm trenches up to 1mm from the trench walls
- Dose of 150mJ and 2min development cleared some of the features and not others. Over exposed wafer second time with 250mJ to clear resist from all areas
- Resist couldn't be cleared from smaller 350um x 650um trenches even after high energy dose (700mJ)
- Manual development in Headway for 2min – 5min

Conclusions

- Developed a spraycoat recipe for coating resist in 350x650 wide and 350um deep cavities
- Final recipe
 - Resist mix: 5% SPR 220-7, 35% Ethyl Lactate and 60% MEK
 - Dispense rate: 9ul/s
 - Pressure: 600 mbar
 - Passes: 12
- Resist thickness in the central 100um x 100um area at the bottom of trench 2.7um \pm 0.3um
- Tested recipe for deep trench lithography applications with ASML and was able to resolve 4um features in large areas

Acknowledgements

- Jason Parker, Pierre Ponce, J Provine
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